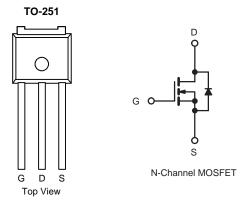


N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A)	Q _g (Typ.)			
30	0.07 at V _{GS} = 10 V	53	19 nC			
	0.09 at V _{GS} = 4.5 V	48	19110			



FEATURES

- Halogen-free
- TrenchFET® Gen III Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested



APPLICATIONS

- DC/DC Conversion
 - System Power

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	± 20	v	
-	T _C = 25 °C		53		
Continuous Drain Current (T _{.1} = 150 °C)	$T_C = 70 ^{\circ}C$	I _D	41		
Continuous Brain Current (1) = 100 C)	T _A = 25 °C	ן טי	14 ^{b, c}	A	
	T _A = 70 °C		10 ^{b, c}		
Pulsed Drain Current		I _{DM}	165		
Avalanche Current L = 0.1 mH		I _{AS}	25		
Avalanche Energy	L=0.11IIII	E _{AS}	40	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	I.	15	Α	
Continuous Source-Diam Diode Current	T _A = 25 °C	ls =	2.9 ^{b, c}	^	
	T _C = 25 °C		28		
Maximum Power Dissipation	T _C = 70 °C	P _D	18	w	
Maximum Power Dissipation	T _A = 25 °C	LD	3.5 ^{b, c}	VV	
	T _A = 70 °C		2.2 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	
Soldering Recommendations (Peak Tempera		260			

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient	t ≤ 10 s	R _{thJA}	29	36	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	3.6	4.5	O/ VV		

- a. Based on T_C = 25 °C.
 b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.



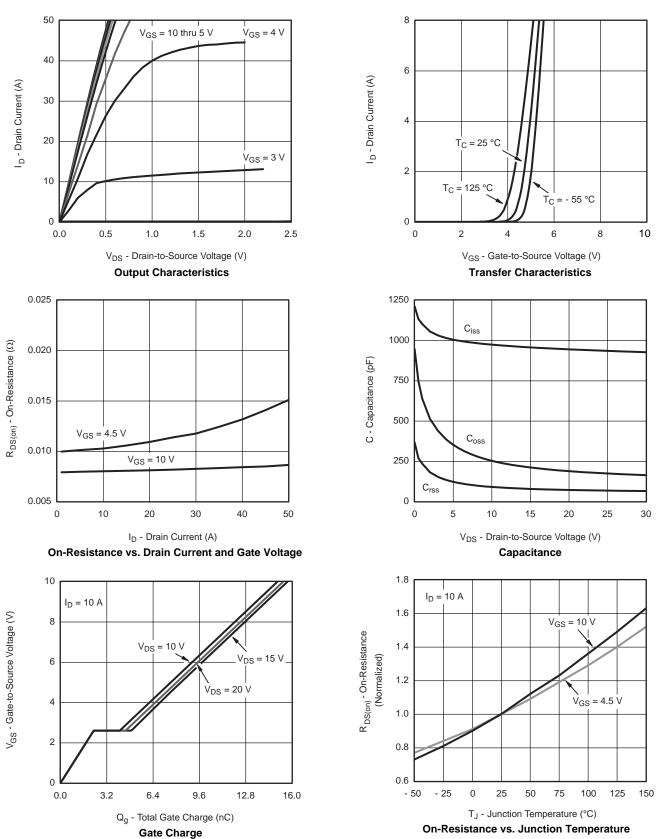
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	•		I.		I.	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	N_{DS}/T_J $I_D = 250 \mu A$		33		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 5		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$	1.2		3.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Oata Waltana Busin Oamani	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
Zero Gate Voltage Drain Current		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			5	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	15			Α
Danie Common Co Olote Desistence		$V_{GS} = 10 \text{ V}, I_{D} = 10 \text{ A}$	0.070			
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_{D} = 7 \text{ A}$		0.090		Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 10 A		24		S
Dynamic ^b			I.	•		
Input Capacitance	C _{iss}			1400		pF
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		200		
Reverse Transfer Capacitance	C _{rss}			150		
Total Gate Charge		$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 10 \text{ A}$		33		nC
	Q _g			18		
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		7.3		
Gate-Drain Charge	Q _{gd}			6.2		
Gate Resistance	R _g	f = 1 MHz	0.2	0.8	1.6	Ω
Turn-On Delay Time	t _{d(on)}			15	30	ns
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.5 Ω		12	24	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		13	26	
Fall Time	t _f			10	20	
Turn-On Delay Time	t _{d(on)}			9	18	
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.5 Ω		9	18	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		14	28	
Fall Time	t _f			8	16	
Drain-Source Body Diode Characteristi	cs					
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			16	Α
Pulse Diode Forward Current	I _{SM}				32	
Body Diode Voltage	V_{SD}	$I_S = 3 \text{ A}, V_{GS} = 0 \text{ V}$		0.78	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			17	34	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 10 A, dl/dt = 100 A/μs, T _{.I} = 25 °C		9.5	19	nC
Reverse Recovery Fall Time	t _a	i _F = 10 Λ, αίναι = 100 Λ/μs, 1 _J = 25 °C		10		
everse Recovery Rise Time t _b				7		ns

Notes

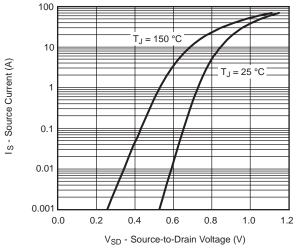
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

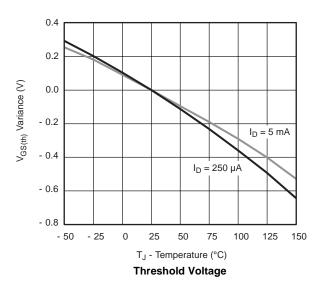








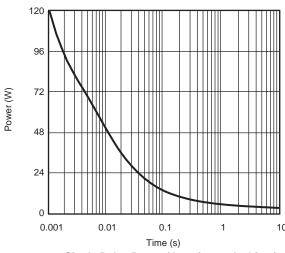
Source-Drain Diode Forward Voltage



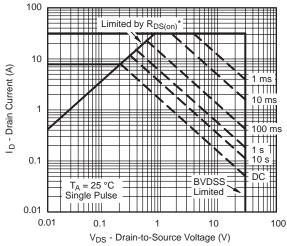
0.06 $I_D = 10^{\circ} A$ 0.05 $R_{DS(on)}$ - On-Resistance (Ω) 0.04 0.03 $T_J = 125$ °C 0.02 0.01 $T_J = 25 \, ^{\circ}C$ 0.00 3 0 1 2 4 5

V_{GS} - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage



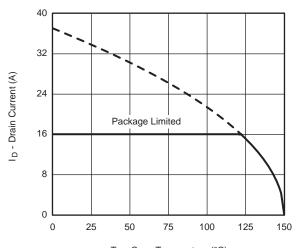
Single Pulse Power (Junction-to-Ambient)



* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

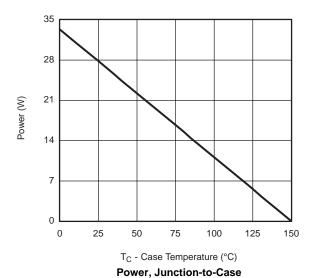
Safe Operating Area, Junction-to-Ambient

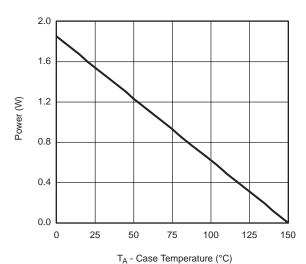




T_C - Case Temperature (°C)

Current Derating*

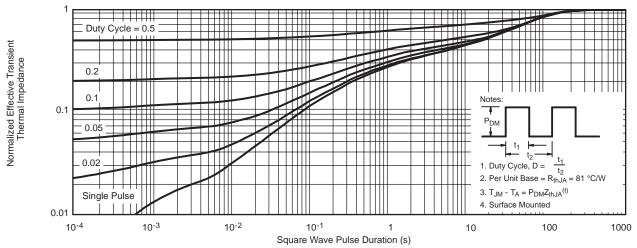




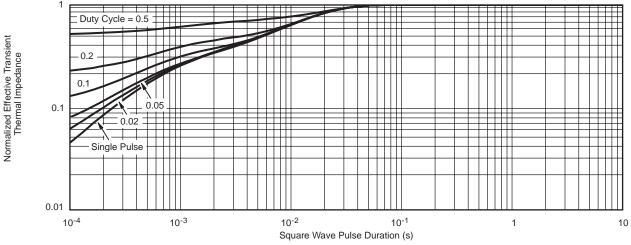
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





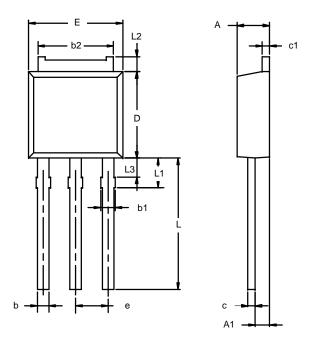




Normalized Thermal Transient Impedance, Junction-to-Case



TO-251AA (DPAK)



Note: Dimension L3 is for reference only.

	MILLIM	IETERS	INC	HES		
Dim	Min	Max	Min	Max		
Α	2.21	2.38	0.087	0.094		
A 1	0.89	1.14	0.035	0.045		
b	0.71	0.89	0.028	0.035		
b1	0.76	1.14	0.030	0.045		
b2	5.23	5.43	0.206	0.214		
С	0.46	0.58	0.018	0.023		
с1	0.46	0.58	0.018	0.023		
D	5.97	6.22	0.235	0.245		
Е	6.48	6.73	0.255	0.265		
е	2.28 BSC		0.090	90 BSC		
L	3.89	9.53	0.153	0.375		
L1	1.91	2.28	0.075	0.090		
L2	0.89	1.27	0.035	0.050		
L3	1.15	1.52	0.045	0.060		
ECN: S-03946—Rev. E, 09-Jul-01 DWG: 5346						



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